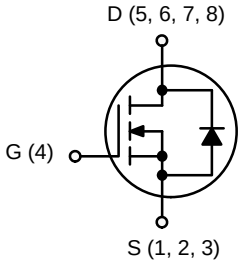
MOSFET – N-Channel, Shielded Gate, POWERTRENCH®

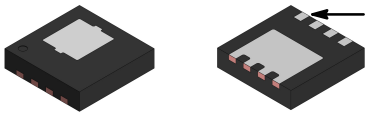
80 V, 64 A, 6.8 mΩ

FDMC007N08LCDC

V_{DS}	$R_{DS(ON)}$ MAX	I_D MAX
80 V	6.8 mΩ @ 10 V	22 A
	11.1 mΩ @ 4.5 V	



N-CHANNEL MOSFET



DUAL COOL® 33
(PQFN8)
CASE 483AY

General Description

This N-Channel MV MOSFET is produced using **onsemi**'s advanced POWERTRENCH process that incorporates Shielded Gate technology. This process has been optimized to minimize on-state resistance and yet maintain superior switching performance with best in class soft body diode.

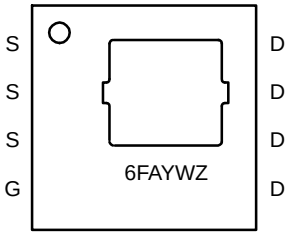
Features

- Shielded Gate MOSFET Technology
- Max $R_{DS(on)}$ = 6.8 mΩ at V_{GS} = 10 V, I_D = 22 A
- Max $R_{DS(on)}$ = 11.1 mΩ at V_{GS} = 4.5 V, I_D = 18 A
- 5 V Drive Capable
- 50% Lower Q_{rr} than Other MOSFET Suppliers
- Lowers Switching Noise/EMI
- MSL1 Robust Package Design
- 100% UIL Tested
- These Devices are Pb-Free, Halogen Free/BFR Free and are RoHS Compliant

Applications

- Primary DC-DC MOSFET
- Synchronous Rectifier in DC-DC and AC-DC
- Motor Drive
- Solar

MARKING DIAGRAM



6F = Specific Device Code
A = Assembly Plant Code
YW = Numeric Date Code
Z = Lot Code

ORDERING INFORMATION

See detailed ordering and shipping information on page 6 of this data sheet.

MAXIMUM RATINGS (T_A = 25 °C unless otherwise noted)

Symbol	Parameter	Value	Unit
V_{DS}	Drain to Source Voltage	80	V
V_{GS}	Gate to Source Voltage	±20	V
I_D	Drain Current: Continuous, T_C = 25 °C (Note 5) Continuous, T_C = 100 °C (Note 5) Continuous, T_A = 25 °C (Note 1a) Pulsed (Note 4)	 64 41 15 339	A
E_{AS}	Single Pulse Avalanche Energy (Note 3)	150	mJ
P_D	Power Dissipation: T_C = 25°C T_A = 25°C (Note 1a)	 57 3	W
T_J, T_{STG}	Operating and Storage Junction Temperature Range	−55 to +150	°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

THERMAL CHARACTERISTICS

Symbol	Parameter	Value	Unit
$R_{\theta JC}$	Thermal Resistance, Junction to Case	2.2	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient (Note 1a)	42	

ELECTRICAL CHARACTERISTICS (T_J = 25 °C unless otherwise noted)

Symbol	Parameter	Test Condition	Min	Typ	Max	Unit
OFF CHARACTERISTICS						
BV_{DSS}	Drain to Source Breakdown Voltage	I_D = 250 μA, V_{GS} = 0 V	80			V
$\Delta BV_{DSS}/\Delta T_J$	Breakdown Voltage Temperature Coefficient	I_D = 250 μA, referenced to 25 °C		67		mV/°C
I_{DSS}	Zero Gate Voltage Drain Current	V_{DS} = 64 V, V_{GS} = 0 V			1	μA
I_{GSS}	Gate to Source Leakage Current	V_{GS} = ±20 V, V_{DS} = 0 V			±100	nA
ON CHARACTERISTICS						
$V_{GS(th)}$	Gate to Source Threshold Voltage	V_{GS} = V_{DS}, I_D = 130 μA	1.0	1.5	2.5	V
$\Delta V_{GS(th)}/\Delta T_J$	Gate to Source Threshold Voltage Temperature Coefficient	I_D = 130 μA, referenced to 25 °C		−5.2		mV/°C
$R_{DS(on)}$	Static Drain to Source On Resistance	V_{GS} = 10 V, I_D = 22 A		5.1	6.8	mΩ
		V_{GS} = 4.5 V, I_D = 18 A		7.3	11.1	
		V_{GS} = 10 V, I_D = 22 A, T_J = 125 °C		9.5	12.5	
g_{FS}	Forward Transconductance	V_{DS} = 5 V, I_D = 22 A		80		S
DYNAMIC CHARACTERISTICS						
C_{iss}	Input Capacitance	V_{DS} = 40 V, V_{GS} = 0 V, f = 1 MHz		2195	3070	pF
C_{oss}	Output Capacitance			521	730	pF
C_{rss}	Reverse Transfer Capacitance			25	40	pF
R_g	Gate Resistance		0.1	0.5	0.9	Ω
SWITCHING CHARACTERISTICS						
$t_{d(on)}$	Turn-On Delay Time	V_{DD} = 40 V, I_D = 22 A, V_{GS} = 10 V, R_{GEN} = 6 Ω		11	21	ns
t_r	Rise Time			3	10	ns
$t_{d(off)}$	Turn-Off Delay Time			36	58	ns
t_f	Fall Time			4	10	ns
Q_g	Total Gate Charge	V_{GS} = 0 V to 10 V, V_{DD} = 40 V, I_D = 22 A		31	44	nC
		V_{GS} = 0 V to 4.5 V, V_{DD} = 40 V, I_D = 22 A		15	21	nC
Q_{gs}	Gate to Source Charge	V_{DD} = 40 V, I_D = 22 A		5		nC
Q_{gd}	Gate to Drain “Miller” Charge	V_{DD} = 40 V, I_D = 22 A		4		nC
Q_{oss}	Output Charge	V_{DD} = 40 V, V_{GS} = 0 V		29		nC
Q_{sync}	Total Gate Charge Sync	V_{DS} = 0 V, I_D = 22 A		28		nC
DRAIN-SOURCE DIODE CHARACTERISTICS						
V_{SD}	Source to Drain Diode Forward Voltage	V_{GS} = 0 V, I_S = 2.5 A (Note 2)		0.7	1.2	V
		V_{GS} = 0 V, I_S = 22 A (Note 2)		0.8	1.3	
t_{rr}	Reverse Recovery Time	I_F = 11 A, di/dt = 300 A/μs		18	32	ns
Q_{rr}	Reverse Recovery Charge			24	38	nC

ELECTRICAL CHARACTERISTICS (T_J = 25 °C unless otherwise noted) (continued)

Symbol	Parameter	Test Condition	Min	Typ	Max	Unit
DRAIN-SOURCE DIODE CHARACTERISTICS						
t_{rr}	Reverse Recovery Time	I_F = 11 A, di/dt = 1000 A/μs		15	26	ns
Q_{rr}	Reverse Recovery Charge			60	96	nC

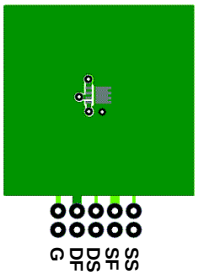
Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

THERMAL CHARACTERISTICS

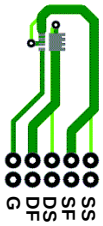
Symbol	Parameter	Value	Unit
$R_{\theta JC}$	Thermal Resistance, Junction to Case (Top Source)	6.0	°C/W
$R_{\theta JC}$	Thermal Resistance, Junction to Case (Bottom Source)	2.2	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient (Note 1a)	42	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient (Note 1b)	105	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient (Note 1c)	29	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient (Note 1d)	40	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient (Note 1e)	19	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient (Note 1f)	23	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient (Note 1g)	30	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient (Note 1h)	79	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient (Note 1i)	17	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient (Note 1j)	26	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient (Note 1k)	12	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient (Note 1l)	16	°C/W

NOTES:

1. $R_{\theta JA}$ is determined with the device mounted on a FR-4 board using a specified pad of 2 oz copper as shown below. $R_{\theta JC}$ is guaranteed by design while $R_{\theta CA}$ is determined by the user's board design.



a) 42 °C/W when mounted on a 1 in^2 pad of 2 oz copper.



b) 105 °C/W when mounted on a minimum pad of 2 oz copper.

c. Still air, 20.9 × 10.4 × 12.7 mm Aluminum Heat Sink, 1 in^2 pad of 2 oz copper
d. Still air, 20.9 × 10.4 × 12.7 mm Aluminum Heat Sink, minimum pad of 2 oz copper
e. Still air, 45.2 × 41.4 × 11.7 mm Aavid Thermalloy Part # 10-L41B-11 Heat Sink, 1 in^2 pad of 2 oz copper
f. Still air, 45.2 × 41.4 × 11.7 mm Aavid Thermalloy Part # 10-L41B-11 Heat Sink, minimum pad of 2 oz copper
g. 200FPM Airflow, No Heat Sink,1 in2 pad of 2 oz copper
h. 200FPM Airflow, No Heat Sink, minimum pad of 2 oz copper
i. 200FPM Airflow, 20.9 × 10.4 × 12.7 mm Aluminum Heat Sink, 1 in^2 pad of 2 oz copper
j. 200FPM Airflow, 20.9 × 10.4 × 12.7 mm Aluminum Heat Sink, minimum pad of 2 oz copper
k. 200FPM Airflow, 45.2 × 41.4 × 11.7 mm Aavid Thermalloy Part # 10-L41B-11 Heat Sink, 1 in^2 pad of 2 oz copper
l. 200FPM Airflow, 45.2 × 41.4 × 11.7 mm Aavid Thermalloy Part # 10-L41B-11 Heat Sink, minimum pad of 2 oz copper

2. Pulse Test: Pulse Width < 300 μs, Duty cycle < 2.0%.
3. E_{AS} of 150 mJ is based on starting T_J = 25 °C; L = 3 mH, I_{AS} = 10 A, V_{DD} = 80 V, V_{GS} = 10 V. 100% test at L = 0.1 mH, I_{AS} = 32 A.
4. Pulsed Id please refer to Figure 11 SOA graph for more details.
5. Computed continuous current limited to Max Junction Temperature only, actual continuous current will be limited by thermal & electro-mechanical application board design.

TYPICAL CHARACTERISTICS

(T_J = 25 °C UNLESS OTHERWISE NOTED)

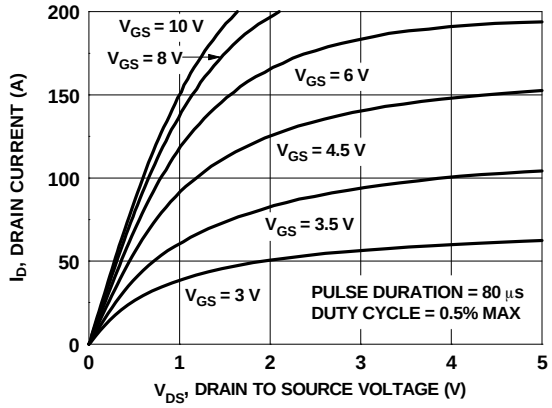


Figure 1. On Region Characteristics

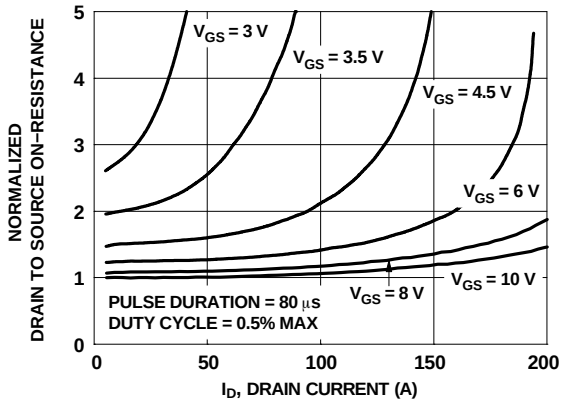


Figure 2. Normalized On-Resistance vs. Drain Current and Gate Voltage

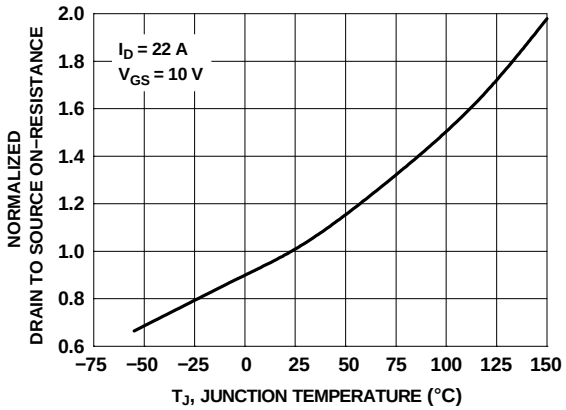


Figure 3. Normalized On-Resistance vs. Junction Temperature

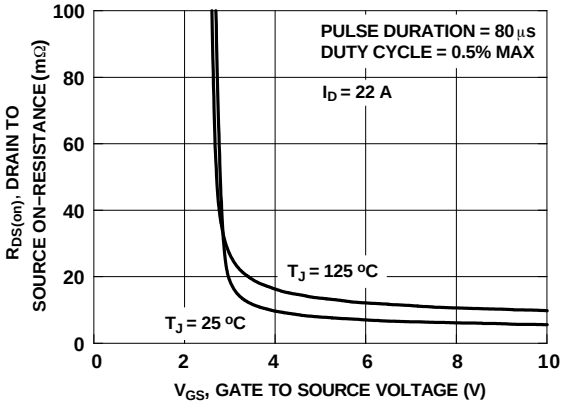


Figure 4. On-Resistance vs. Gate to Source Voltage

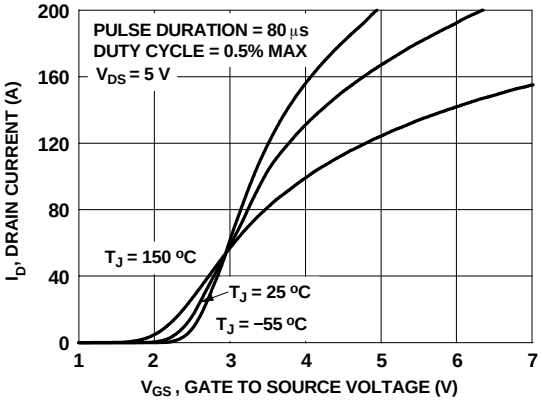


Figure 5. Transfer Characteristics

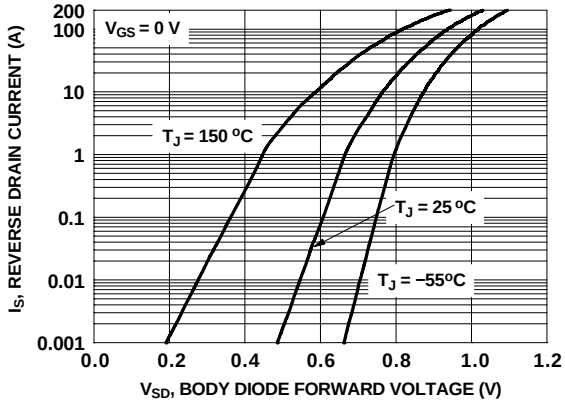


Figure 6. Source to Drain Diode Forward Voltage vs. Source Current

TYPICAL CHARACTERISTICS

(T_J = 25 °C UNLESS OTHERWISE NOTED)

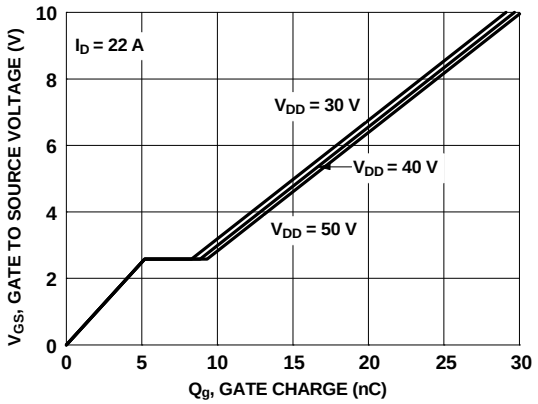


Figure 7. Gate Charge Characteristics

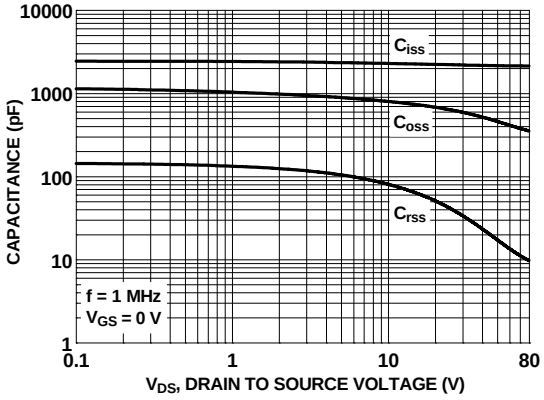


Figure 8. Capacitance vs. Drain to Source Voltage

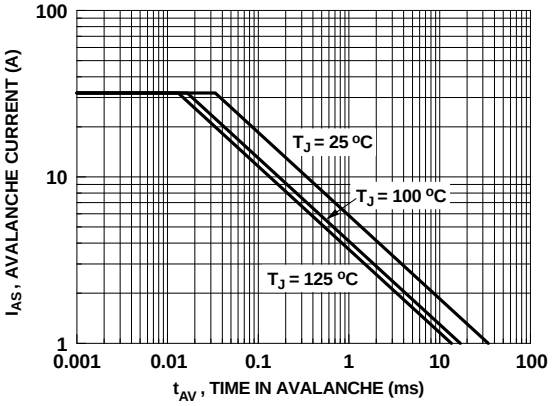


Figure 9. Unclamped Inductive Switching Capability

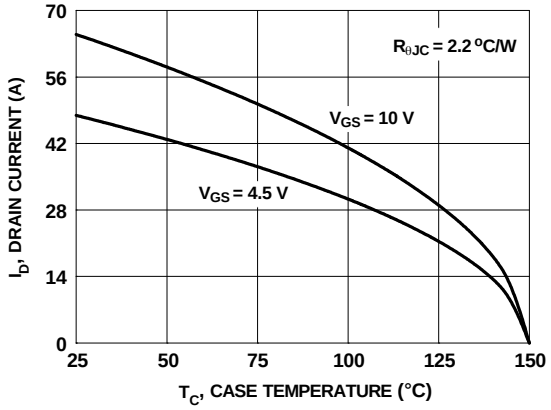


Figure 10. Maximum Continuous Drain Current vs. Case Temperature

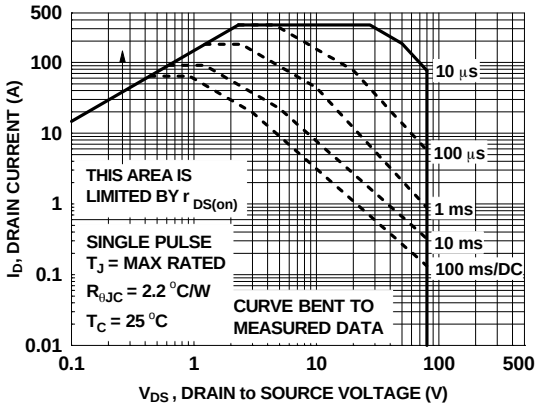


Figure 11. Forward Bias Safe Operating Area

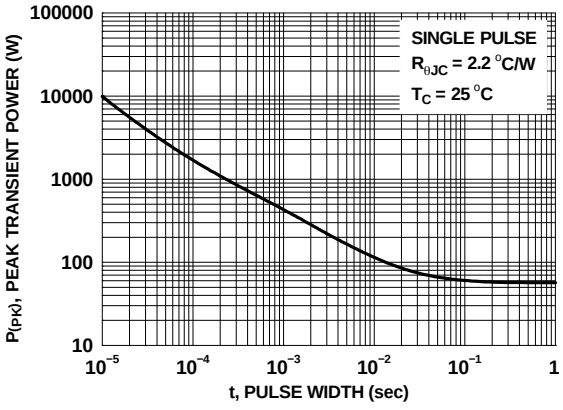


Figure 12. Single Pulse Maximum Power Dissipation

TYPICAL CHARACTERISTICS

(T_J = 25 °C UNLESS OTHERWISE NOTED)

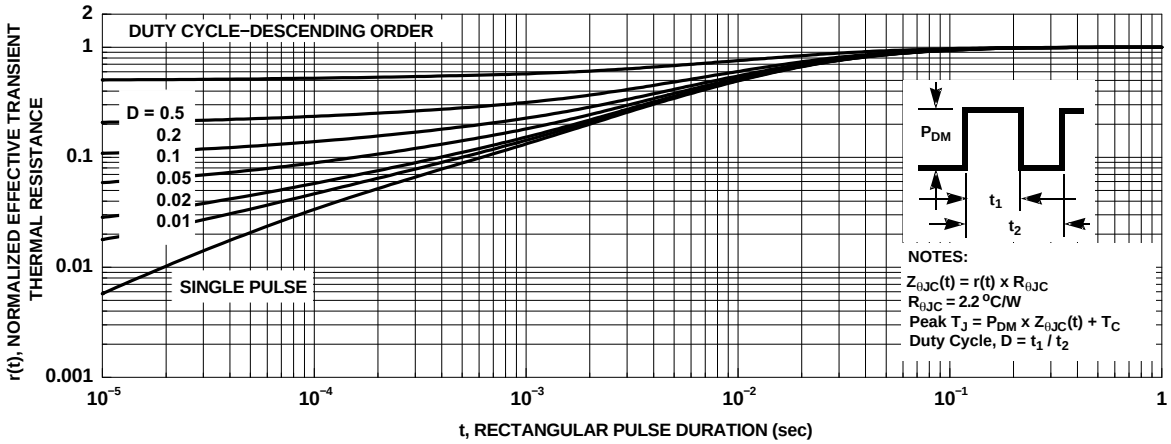


Figure 13. Junction-to-Case Transient Thermal Response Curve

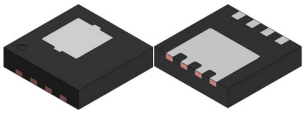
ORDERING INFORMATION

Device	Marking	Package	Reel Size	Tape Width	Quantity
FDMC007N08LCDC	6F	DUAL COOL 33 (PQFN8) (Pb-Free / Halogen Free)	13″	12 mm	3000 Units

REVISION HISTORY

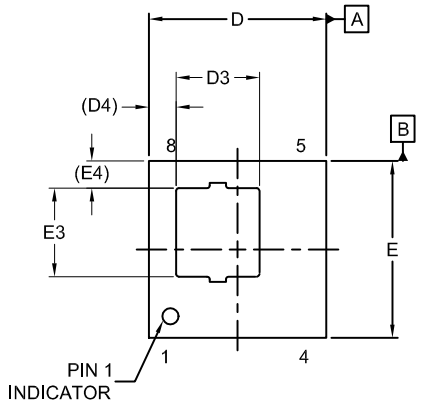
Revision	Description of Changes	Date
6	Update package drawing and Pin 1 location to align with case outline	8/25/2025

This document has undergone updates prior to the inclusion of this revision history table. The changes tracked here only reflect updates made on the noted approval dates.

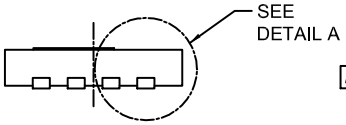


PQFN8 3.3X3.3, 0.65P
CASE 483AY
ISSUE A

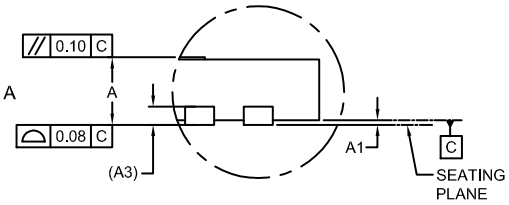
DATE 08 SEP 2021



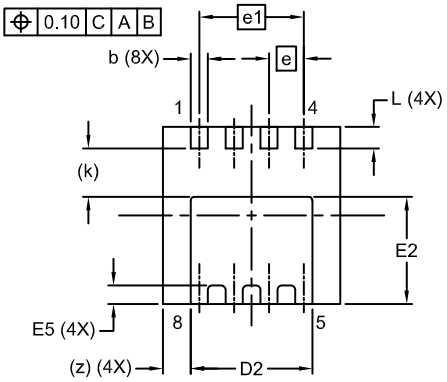
TOP VIEW



FRONT VIEW



DETAIL A
SCALE: 2X

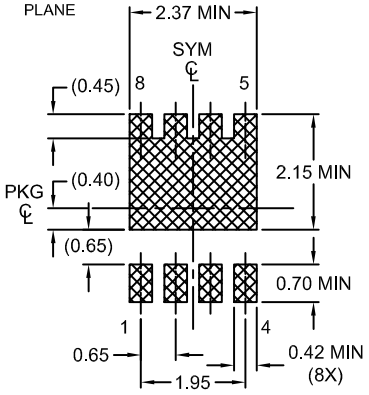


BOTTOM VIEW

NOTES:

1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 2009.
2. CONTROLLING DIMENSION: MILLIMETERS
3. COPLANARITY APPLIES TO THE EXPOSED PADS AS WELL AS THE TERMINALS.
4. DIMENSIONS D1 AND E1 DO NOT INCLUDE MOLD FLASH, PROTRUSIONS, OR GATE BURRS.
5. SEATING PLANE IS DEFINED BY THE TERMINALS. "A1" IS DEFINED AS THE DISTANCE FROM THE SEATING PLANE TO THE LOWEST POINT ON THE PACKAGE BODY.

DIM	MILLIMETERS		
	MIN.	NOM.	MAX.
A	0.70	0.75	0.80
A1	0.00	-	0.05
A3		0.20 REF	
b	0.27	0.32	0.37
D	3.20	3.30	3.40
D2	2.17	2.27	2.37
D3	1.45	1.55	1.65
D4		0.51 REF	
E	3.20	3.30	3.40
E2	1.85	1.95	2.05
E3	1.55	1.65	1.75
E4		0.51 REF	
E5	0.24	0.34	0.44
e		0.65 BSC	
e1		1.95 BSC	
k		0.90 REF	
L	0.30	0.40	0.50
z		0.52 REF	



LAND PATTERN
RECOMMENDATION

*FOR ADDITIONAL INFORMATION ON OUR PB-FREE STRATEGY AND SOLDERING DETAILS, PLEASE DOWNLOAD THE ON SEMICONDUCTOR SOLDERING AND MOUNTING TECHNIQUES REFERENCE MANUAL, SOLDERRM/D.

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DESCRIPTION:	**PQFN8 3.3X3.3, 0.65P**	**PAGE 1 OF 1**

ADDITIONAL INFORMATION

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onsemi Website: www.onsemi.com

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